April 1999



SEMICONDUCTOR TM

FDC6321C Dual N & P Channel , Digital FET

General Description

These dual N & P Channel logic level enhancement mode field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. This device has been designed especially for low voltage applications as a replacement for digital transistors in load switching applications. Since bias resistors are not required this dual digital FET can replace several digital transistors with different bias resistors.

Features

- N-Ch 25 V, 0.68 A, $R_{DS(ON)} = 0.45 \Omega @ V_{GS} = 4.5 V$
- P-Ch -25 V, -0.46 A, $R_{DS(ON)} = 1.1 \Omega @ V_{GS} = -4.5 V.$
- Very low level gate drive requirements allowing direct operation in 3 V circuits. V_{GS(th)} < 1.0V.
- Gate-Source Zener for ESD ruggedness.
 >6kV Human Body Model
- Replace multiple dual NPN & PNP digital transistors.



Absolute Maximum Ratings $T_A = 25^{\circ}C$ unless other wise noted

Symbol	Parameter	N-Channel	P-Channel	Units
$V_{\rm DSS}, V_{\rm CC}$	Drain-Source Voltage, Power Supply Voltage	25	-25	V
$V_{\rm GSS}, V_{\rm IN}$	Gate-Source Voltage,	8	-8	V
I _D , I _O	Drain/Output Current - Continuous	0.68	-0.46	А
	- Pulsed	2	-1.5	
P _D	Maximum Power Dissipation (Note 1a)	0	W	
	(Note 1b)	0		
T_,T _{STG}	Operating and Storage Tempature Ranger	-55 to	°C	
ESD	Electrostatic Discharge Rating MIL-STD-883D Human Body Model (100pf / 1500 Ohm)	6		kV
THERMAL	CHARACTERISTICS			
$R_{_{\!\!\!\!\!\theta J\!A}}$	Thermal Resistance, Junction-to-Ambient (Note 1a)	14	°C/W	
R _{eJC}	Thermal Resistance, Junction-to-Case (Note 1)	6	°C/W	

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	Parameter	Conditions	T	Min	Tum	Max	Unite
Symbol	Parameter	Conditions	l ype	WIN	тур	wax	Units
OFF CHAR							1
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$	N-Ch	25			V
		$V_{GS} = 0 \text{ V}, \ I_{D} = -250 \ \mu\text{A}$	P-Ch	-25			
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temp. Coefficient	I_D = 250 µA, Referenced to 25 °C	N-Ch		26		mV /°C
		$I_D = -250 \ \mu\text{A}$, Referenced to $25 \ ^\circ\text{C}$	P-Ch		-22		
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 20 V, V_{GS} = 0 V,$	N-Ch			1	μA
		$T_{J} = 55^{\circ}$	C			10	
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V},$	P-Ch			-1	μA
		$T_{J} = 55^{\circ}0$	C			-10	
I _{GSS}	Gate - Body Leakage Current	$V_{GS} = 8 \text{ V}, \ V_{DS} = 0 \text{ V}$	N-Ch			100	nA
		$V_{GS} = -8 V, V_{DS} = 0 V$	P-Ch			-100	nA
ON CHARAC	TERISTICS (Note 2)						
$\Delta V_{GS(th)} / \Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	I_{D} = 250 µA, Referenced to 25 °C	N-Ch		-2.6		mV / °C
(-)		$I_{\rm D}$ = -250 µA, Referenced to 25 °C	P-Ch		2.1		
V _{GS(th)}	Gate Threshold Voltage	$V_{\rm DS} = V_{\rm GS}, \ I_{\rm D} = 250 \mu {\rm A}$	N-Ch	0.65	0.8	1.5	V
		$V_{\rm DS} = V_{\rm GS}, \ I_{\rm D} = -250 \ \mu {\rm A}$	P-Ch	-0.65	-0.86	-1.5	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 0.5 \text{ A}$	N-Ch		0.33	0.45	Ω
		T _J =125°	C		0.51	0.72	Ť
		$V_{GS} = 2.7 \text{ V}, I_{D} = 0.25 \text{ A}$			0.44	0.6	Ť
		$V_{GS} = -4.5 \text{ V}, \ \text{I}_{\text{D}} = -0.5 \text{ A}$	P-Ch		0.87	1.1	İ
		T _J =125°	°C		1.21	1.8	İ
		V _{GS} = -2.7 V, I _D = -0.25 A			1.22	1.5	Ì
I _{D(ON)}	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$	N-Ch	1			А
		$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$	P-Ch	-1			
9 _{FS}	Forward Transconductance	$V_{\rm DS} = 5 \text{ V}, \ \text{I}_{\rm D} = 0.5 \text{ A}$	N-Ch		1.45		S
		$V_{DS} = -5 V, I_{D} = -0.5 A$	P-Ch		0.8		
DYNAMIC CH	HARACTERISTICS		1				
C _{iss}	Input Capacitance	N-Channel	N-Ch		50		pF
		$V_{DS} = 10 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$	P-Ch		63		
C _{oss}	Output Capacitance	f = 1.0 MHz	N-Ch		28		pF
		P-Channel	P-Ch		34		
	Reverse Transfer Capacitance	V_{DS} = -10 V, V_{GS} = 0V,	N-Ch		9		pF
C _{rss}							

Electric	cal Characteristics $(T_A = 2)$	5 °C unless otherwise noted)					
SWITCHING	G CHARACTERISTICS (Note 2)						
Symbol	Parameter	ter Conditions		Min	Тур	Max	Units
t _{D(on)}	Turn - On Delay Time	N-Channel	N-Ch		3	6	nS
		$V_{DD} = 6 V, I_{D} = 0.5 A,$	P-Ch		7	20	
t,	Turn - On Rise Time	$V_{_{GS}}$ = 4.5 V, $R_{_{GEN}}$ = 50 Ω	N-Ch		8	16	nS
			P-Ch		9	18	
t _{D(off)}	Turn - Off Delay Time	P-Channel	N-Ch		17	30	nS
		$V_{DD} = -6 \text{ V}, \text{ I}_{D} = -0.5 \text{ A},$	P-Ch		55	110	
t,	Tum - Off Fall Time	V_{Gen} = -4.5 V, R_{GEN} = 50 Ω	N-Ch		13	25	nS
			P-Ch		35	70	
Q _g Total Gate Charge		N-Channel	N-Ch		1.64	2.3	nC
		$V_{DS} = 5 \text{ V}, \text{ I}_{D} = 0.5 \text{ A},$	P-Ch		1.1	1.5	
Q_{gs}	Gate-Source Charge	$V_{GS} = 4.5 V$	N-Ch		0.38		nC
		P- Channel	P-Ch		0.32		
Q_{gd}	Gate-Drain Charge	$V_{DS} = -5 V,$	N-Ch		0.45		nC
		$I_{\rm D}$ = -0.25 A, $V_{\rm GS}$ = -4.5 V	P-Ch		0.25		
DRAIN-SOU	RCE DIODE CHARACTERISTICS AND MAX	KIMUM RATINGS			1		
I _s	Maximum Continuous Drain-Source Diode	Forward Current	N-Ch			0.3	A
			P-Ch			-0.5	
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 0.5 \text{ A}$ (Note)	N-Ch		0.83	1.2	V
		T _J =125	S°C		0.69	0.85	-
		$V_{GS} = 0 V, I_{S} = -0.5 A$ (Note)	P-Ch		-0.89	-1.2	-
2. Pulse Test: 1	bulse Width ≤ 300µs, Duty Cycle ≤ 2.0%. h. 140°C/W on a 0.125 in ² pad of 202 copper. b. 40° C/W on a 0.125 in ² b. 40° C/W on a 0.125 in ² pad of	180 ⁰ C/W on a 0.005 in ² of pad of 2oz copper.					



FDC6321C.RevB





FDC6321C.RevB



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August 1999, Rev. C



July 1999, Rev. C



September 1998, Rev. A

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